

4226M-VB Datasheet **Dual N-Channel 30 V (D-S) MOSFET**

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)			
30	0.016 at V _{GS} = 10 V	8.5	7.1			
30	0.020 at V _{GS} = 4.5 V	7.6	/.1			

FEATURES

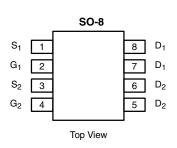
- Trench Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC

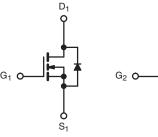


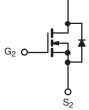
COMPLIANT

APPLICATIONS

- Notebook System Power
- Low Current DC/DC







N-Channel MOSFET

N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage	V_{GS}	± 20			
	T _C = 25 °C		8.5		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	7.5		
Continuous Brain Gunent (1) = 100 0)	T _A = 25 °C	'D	7.2 ^{b, c}		
	T _A = 70 °C		5.9 ^{b, c}		
Pulsed Drain Current		I _{DM}	30	A	
Source-Drain Current Diode Current	T _C = 25 °C	I _S	2.8	Α	
Source-Drain Gurrent blode Gurrent	T _A = 25 °C	'S	1.8 ^{b, c}		
Pulsed Source-Drain Current	I _{SM}	30			
Single Pulse Avalanche Current L = 0.1		I _{AS}	10		
Single Pulse Avalanche Energy	L = 0.111111	E _{AS}	5		
	T _C = 25 °C		3.1		
Maximum Power Dissipation	T _C = 70 °C	P _D	2.0	w	
Maximum Fower Dissipation	T _A = 25 °C		2.0 ^{b, c}		
	T _A = 70 °C		1.25 ^{b, c}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS								
Parameter	Symbol	Тур.	Max.	Unit				
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	52	62.5	°C/W			
Maximum Junction-to-Foot (Drain)	Steady-State	R_{thJF}	30	40	7 5/11			

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 110 °C/W.

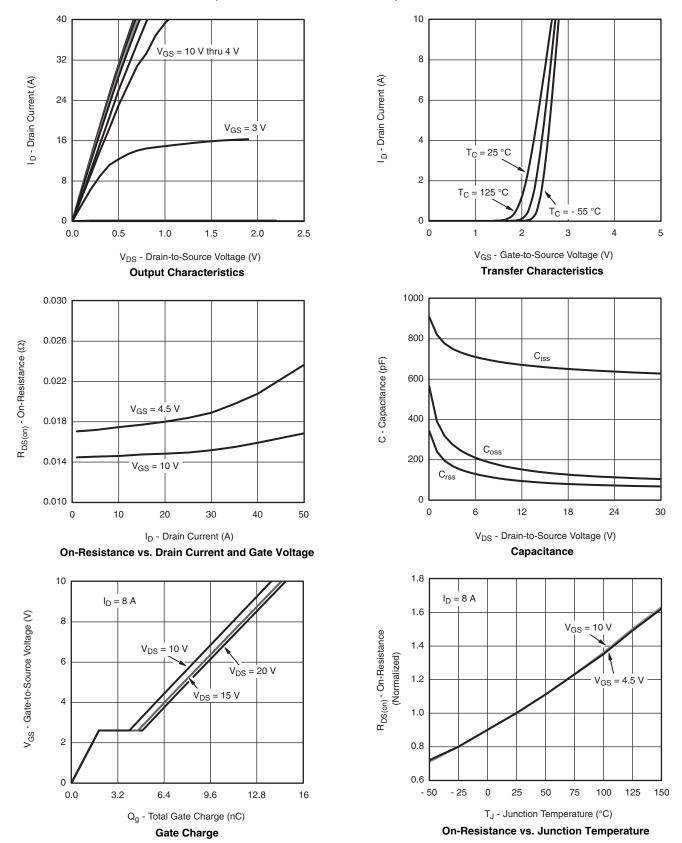


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•	,					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$ $I_D = 250 \mu A$			3.0		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.2		mV/°C	
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			100	nA	
7 0	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V		1			
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, TJ = 55 °C			10	μΑ	
On -State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	20			Α	
h	_	V _{GS} = 10 V, I _D = 8 A		0.016		Ω	
Drain-Source On-State Resistance ^D	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 5 A		0.020			
Forward Transconductance ^b	9 _{fs}	V _{DS} = 15 V, I _D = 8 A		27		S	
Dynamic ^a		<u> </u>					
Input Capacitance	C _{iss}			660			
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, I _D = 1 MHz		140		pF	
Reverse Transfer Capacitance	C _{rss}	1		86			
Total Gate Charge	Q _g	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 8 A		14.5	22	nC	
				7.1	11		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 8 \text{ A}$		1.9			
Gate-Drain Charge	Q_{gd}]		2.7			
Gate Resistance	R_{g}	f = 1 MHz	0.5	2.6	5.2	Ω	
Turn-On Delay Time	t _{d(on)}			14	28		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_L = 3 \Omega$		45	80		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		18	35	1	
Fall Time	t _f]		12	24		
Turn-On Delay Time	t _{d(on)}			7	14	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		15	30		
Fall Time	t _f	j		7	14		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.8	^	
Pulse Diode Forward Current ^a	I _{SM}				30	A	
Body Diode Voltage	V _{SD}	I _S = 2 A		0.77	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			17	34	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1		9	18	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		10		_	
Reverse Recovery Rise Time	t _b			7		nS	

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



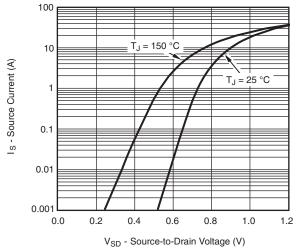
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



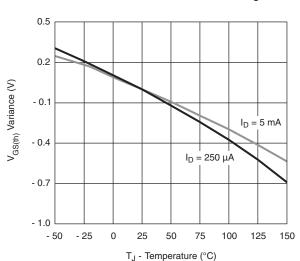
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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

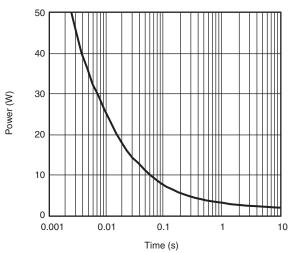


Source-Drain Diode Forward Voltage

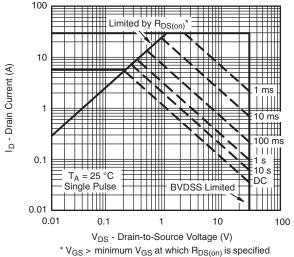


Threshold Voltage

On-Resistance vs. Gate-to-Source Voltage



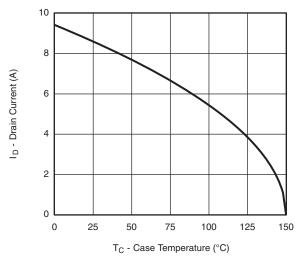
Single Pulse Power, Junction-to-Ambient



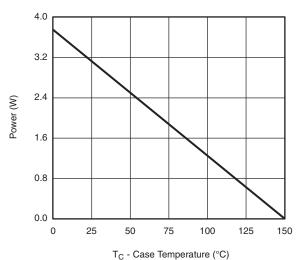
Safe Operating Area, Junction-to-Ambient



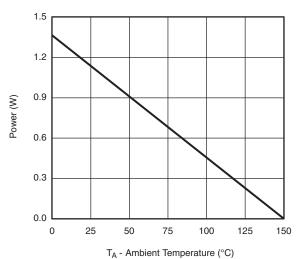
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Current Derating*





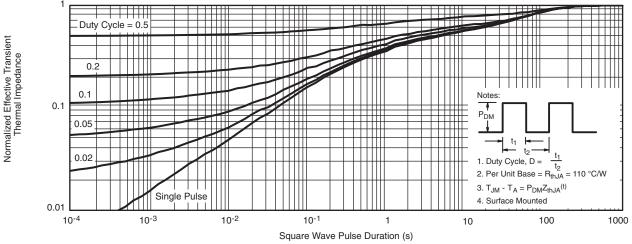


Power Derating, Junction-to-Ambient

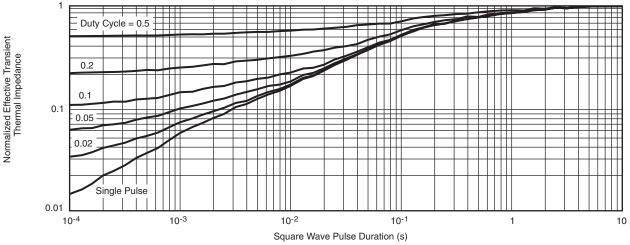
 $^{^*}$ The power dissipation P_D is based on $T_{J(max)}$ = 150 $^{\circ}$ C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



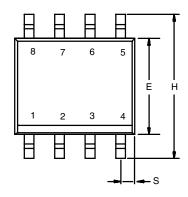
Normalized Thermal Transient Impedance, Junction-to-Ambient

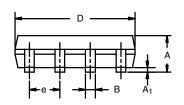


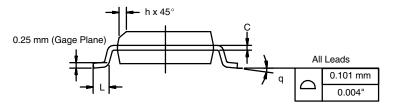
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







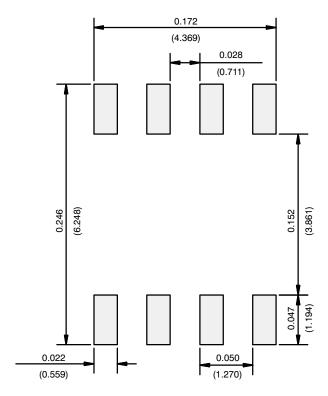
	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06						

DWG: 5498

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RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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